Environmental Stress Screening - Its Quantification, Optimization and Management

Description: With the growth of the electronics industry, environmental stress screening (ESS) has become an essential tool for the production of failure-free electronic assemblies, modules and systems. This handbook provides a thorough introduction and guide to ESS methods and applications. Numerous case histories illustrate practical uses of ESS.

The authors cover the theoretical aspects of environmental stress screening thoroughly, including: history and evolution of the field; definitions and related concepts; and various types of environmental stress screening.

Features
- Up-to-date military standards and directives
- Handy guides and tables
- Dynamic procedures and tailoring techniques
- Case histories from government and industry
- FORTRAN programs for environmental stress screening

Contents: Problems and reference sections are included in each chapter.

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- What This Book Offers?

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